# Driver Transistors NPN Silicon

#### MAXIMUM RATINGS

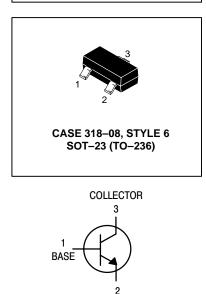
Rating	Symbol	MMBTA05	MMBTA06	Unit
Collector-Emitter Voltage	V <sub>CEO</sub>	60	80	Vdc
Collector-Base Voltage	V <sub>CBO</sub>	60	80	Vdc
Emitter-Base Voltage	V <sub>EBO</sub>	4.0		Vdc
Collector Current — Continuous	۱ <sub>C</sub>	500		mAdc

#### THERMAL CHARACTERISTICS

Characteristic	Symbol	Мах	Unit
Total Device Dissipation FR–5 Board <sup>(1)</sup>	PD	225	mW
T <sub>A</sub> = 25°C Derate above 25°C		1.8	mW/°C
Thermal Resistance, Junction to Ambient	$R_{\theta JA}$	556	°C/W
Total Device Dissipation Alumina Substrate, <sup>(2)</sup> $T_A = 25^{\circ}C$	PD	300	mW
Derate above 25°C		2.4	mW/°C
Thermal Resistance, Junction to Ambient	$R_{\thetaJA}$	417	°C/W
Junction and Storage Temperature	T <sub>J</sub> , T <sub>stg</sub>	-55 to +150	°C



\*ON Semiconductor Preferred Device



#### EMITTER

0.1

#### **DEVICE MARKING**

MMBTA05LT1 = 1H; MMBTA06LT1 = 1GM

**ELECTRICAL CHARACTERISTICS** (T<sub>A</sub> = 25°C unless otherwise noted)

Characteristic		Symbol	Min	Max	Unit
OFF CHARACTERISTICS					
Collector–Emitter Breakdown Voltage (3) ( $I_C = 1.0 \text{ mAdc}, I_B = 0$ )	MMBTA05 MMBTA06	V <sub>(BR)CEO</sub>	60 80		Vdc
Emitter–Base Breakdown Voltage ( $I_E = 100 \ \mu Adc, I_C = 0$ )		V <sub>(BR)EBO</sub>	4.0	—	Vdc
Collector Cutoff Current (V <sub>CE</sub> = 60 Vdc, I <sub>B</sub> = 0)		ICES	—	0.1	μAdc
Collector Cutoff Current ( $V_{CB} = 60 \text{ Vdc}, I_E = 0$ )	MMBTA05	I <sub>CBO</sub>	_	0.1	μAdc

MMBTA06

1. FR–5 =  $1.0 \times 0.75 \times 0.062$  in.

 $(V_{CB} = 80 \text{ Vdc}, I_E = 0)$ 

2. Alumina =  $0.4 \times 0.3 \times 0.024$  in. 99.5% alumina.

3. Pulse Test: Pulse Width  $\leq$  300 µs, Duty Cycle  $\leq$  2.0%.

Preferred devices are ON Semiconductor recommended choices for future use and best overall value.

## MMBTA05LT1 MMBTA06LT1

## **ELECTRICAL CHARACTERISTICS** ( $T_A = 25^{\circ}C$ unless otherwise noted) (Continued)

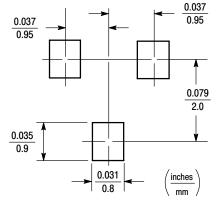
Characteristic		Min	Max	Unit
ON CHARACTERISTICS				
DC Current Gain ( $I_C = 10 \text{ mAdc}, V_{CE} = 1.0 \text{ Vdc}$ ) ( $I_C = 100 \text{ mAdc}, V_{CE} = 1.0 \text{ Vdc}$ )	h <sub>FE</sub>	100 100		—
Collector–Emitter Saturation Voltage $(I_{C} = 100 \text{ mAdc}, I_{B} = 10 \text{ mAdc})$	V <sub>CE(sat)</sub>	—	0.25	Vdc
Base–Emitter On Voltage ( $I_c = 100 \text{ mAdc}, V_{cE} = 1.0 \text{ Vdc}$ )	V <sub>BE(on)</sub>	—	1.2	Vdc
SMALL-SIGNAL CHARACTERISTICS				
Current–Gain — Bandwidth Product <sup>(4)</sup> (I <sub>C</sub> = 10 mA, V <sub>CE</sub> = 2.0 V, f = 100 MHz)	f <sub>T</sub>	100	—	MHz

4.  $f_T$  is defined as the frequency at which  $|h_{fe}|$  extrapolates to unity.

### **INFORMATION FOR USING THE SOT-23 SURFACE MOUNT PACKAGE**

#### MINIMUM RECOMMENDED FOOTPRINT FOR SURFACE MOUNTED APPLICATIONS

Surface mount board layout is a critical portion of the total design. The footprint for the semiconductor packages must be the correct size to insure proper solder connection interface between the board and the package. With the correct pad geometry, the packages will self align when subjected to a solder reflow process.



SOT-23

#### SOT-23 POWER DISSIPATION

The power dissipation of the SOT–23 is a function of the pad size. This can vary from the minimum pad size for soldering to a pad size given for maximum power dissipation. Power dissipation for a surface mount device is determined by  $T_{J(max)}$ , the maximum rated junction temperature of the die,  $R_{\theta JA}$ , the thermal resistance from the device junction to ambient, and the operating temperature,  $T_A$ . Using the values provided on the data sheet for the SOT–23 package,  $P_D$  can be calculated as follows:

$$P_{D} = \frac{T_{J(max)} - T_{A}}{R_{\theta JA}}$$

The values for the equation are found in the maximum ratings table on the data sheet. Substituting these values into the equation for an ambient temperature  $T_A$  of 25°C, one can calculate the power dissipation of the device which in this case is 225 milliwatts.

$$P_{D} = \frac{150^{\circ}C - 25^{\circ}C}{556^{\circ}C/W} = 225 \text{ milliwatts}$$

The 556°C/W for the SOT–23 package assumes the use of the recommended footprint on a glass epoxy printed circuit board to achieve a power dissipation of 225 milliwatts. There are other alternatives to achieving higher power dissipation from the SOT–23 package. Another alternative would be to use a ceramic substrate or an aluminum core board such as Thermal Clad<sup>™</sup>. Using a board material such as Thermal Clad, an aluminum core board, the power dissipation can be doubled using the same footprint.

#### SOLDERING PRECAUTIONS

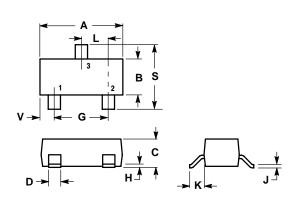
The melting temperature of solder is higher than the rated temperature of the device. When the entire device is heated to a high temperature, failure to complete soldering within a short time could result in device failure. Therefore, the following items should always be observed in order to minimize the thermal stress to which the devices are subjected.

- Always preheat the device.
- The delta temperature between the preheat and soldering should be 100°C or less.\*
- When preheating and soldering, the temperature of the leads and the case must not exceed the maximum temperature ratings as shown on the data sheet. When using infrared heating with the reflow soldering method, the difference shall be a maximum of 10°C.
- The soldering temperature and time shall not exceed 260°C for more than 10 seconds.
- When shifting from preheating to soldering, the maximum temperature gradient shall be 5°C or less.
- After soldering has been completed, the device should be allowed to cool naturally for at least three minutes. Gradual cooling should be used as the use of forced cooling will increase the temperature gradient and result in latent failure due to mechanical stress.
- Mechanical stress or shock should not be applied during cooling.

\* Soldering a device without preheating can cause excessive thermal shock and stress which can result in damage to the device.

#### PACKAGE DIMENSIONS

SOT-23 (TO-236) CASE 318-08 ISSUE AF



NOTES:

 DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.

CONTROLLING DIMENSION: INCH.

 MAXIMUM LEAD THICKNESS INCLUDES LEAD FINISH THICKNESS. MINIMUM LEAD THICKNESS IS THE MINIMUM THICKNESS OF BASE MATERIAL.

	INCHES		MILLIN	IETERS
DIM	MIN	MAX	MIN	MAX
Α	0.1102	0.1197	2.80	3.04
В	0.0472	0.0551	1.20	1.40
С	0.0350	0.0440	0.89	1.11
D	0.0150	0.0200	0.37	0.50
G	0.0701	0.0807	1.78	2.04
Н	0.0005	0.0040	0.013	0.100
J	0.0034	0.0070	0.085	0.177
К	0.0140	0.0285	0.35	0.69
L	0.0350	0.0401	0.89	1.02
S	0.0830	0.1039	2.10	2.64
٧	0.0177	0.0236	0.45	0.60

STYLE 6: PIN 1. BASE 2. EMITTER 3. COLLECTOR

Thermal Clad is a trademark of the Bergquist Company

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